

Automatic generation of EFSMs and HLDDs for functional ATPG

Tšepurov, Anton; Guglielmo, Giuseppe di; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Viilukas, Taavi** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 143-146 : ill

Mutation analysis with high-level decision diagrams

Hantson, Hanno; **Raik, Jaan**; **Jenihhin, Maksim**; **Tšepurov, Anton**; **Ubar, Raimund-Johannes**; Guglielmo, Giuseppe di; Fummi, Franco LATW2010 : 11th Latin-American TestWorkshop, March 28-31, 2010, Punta del Este, Uruguay 2010 / [6] p. [CD-ROM] <https://ieeexplore.ieee.org/document/5550336>